

COMPLIANT HALOGEN

FREE

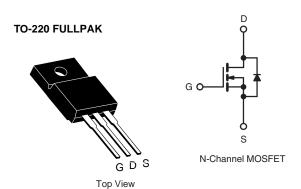
### HFS13N50S-VB Datasheet

# N-Channel 550V (D-S) Power MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	55	550				
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.26				
Q <sub>g</sub> max. (nC)	150	150				
Q <sub>gs</sub> (nC)	12	12				
Q <sub>gd</sub> (nC)	25	25				
Configuration	Sing	Single				

#### **FEATURES**

- Optimal Design
  - Low Area Specific On-Resistance
  - Low Input Capacitance (Ciss)
  - Reduced Capacitive Switching Losses
  - High Body Diode Ruggedness
  - Avalanche Energy Rated (UIS)
- Optimal Efficiency and Operation
  - Low Cost
  - Simple Gate Drive Circuitry
  - Low Figure-of-Merit (FOM): Ron x Qa
  - Fast Switching



#### **APPLICATIONS**

- Consumer Electronics
  - Displays (LCD or Plasma TV)
- Server and Telecom Power Supplies
  - SMPS
- Industrial
  - Welding
  - Induction Heating
  - Motor Drives
- Battery Chargers
- SMPS
  - Power Factor Correction (PFC)

ABSOLUTE MAXIMUM RATINGS ( $T_C$					1	
PARAMETER		SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			$V_{DS}$	550		
Gate-Source Voltage			V	± 20	V	
Gate-Source Voltage AC (f > 1 Hz)			V <sub>GS</sub>	30	1	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	$V_{GS}$ at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$	,	18			
	VGS at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	11	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	56		
Linear Derating Factor				2.2	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	281	mJ	
Maximum Power Dissipation			$P_{D}$	60	W	
Operating Junction and Storage Temperature Range	е		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		-17.1714	24	1//	
Reverse Diode dV/dt <sup>d</sup>		dV/dt	0.36	V/ns		
Soldering Recommendations (Peak Temperature)	for 1	0 s		300°	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 10 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 7.5 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ , starting  $T_J = 25$  °C.

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THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.45	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		•			•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		550	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I <sub>D</sub> = 250 μA	-	0.56	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2	-	4	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V		1	-	1	μΑ
Zelo Gate Voltage Dialii Current	I <sub>DSS</sub>	$V_{DS} = 400 \text{ V}$	$V_{\rm S} = 0 \ V_{\rm T} = 125 \ ^{\circ}{\rm C}$	1	-	10	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}$	$I_D = 10 \text{ A}$	-	0.26	-	Ω
Forward Transconductance	9 <sub>fs</sub>	$V_{DS}$	$= 50 \text{ V}, I_D = 10 \text{ A}$	ı	12	-	S
Dynamic							
Input Capacitance	$C_{iss}$	_	$V_{GS} = 0 V$ ,	-	3094	-	
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 100 \text{ V},$	-	152	-	
Reverse Transfer Capacitance	$C_{rss}$		f = 1 MHz		13	-	pF
Effective output capacitance, energy related <sup>a</sup>	$C_{\text{o(er)}}$	V <sub>GS</sub> = 0 V,		-	131	-	
Effective output capacitance, time related <sup>b</sup>	$C_{o(tr)}$	V <sub>D</sub>	V <sub>DS</sub> = 0 V to 400 V		189	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = 10 V		-	80	150	nC
Gate-Source Charge	$Q_{gs}$			-	12	-	
Gate-Drain Charge	$Q_{gd}$			-	25	-	
Turn-On Delay Time	t <sub>d(on)</sub>			-	24	50	
Rise Time	t <sub>r</sub>	$V_{DD} = 400 \text{ V}, I_{D} = 10 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{g} = 9.1 \Omega$		-	31	62	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	117	176	
Fall Time	t <sub>f</sub>			-	56	112	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	1.8	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	80	- A
Diode Forward Voltage	V <sub>SD</sub>	$T_J = 25  ^{\circ}\text{C},  I_S = 10  \text{A},  V_{GS} = 0  \text{V}$		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 10 A, dl/dt = 100 A/μs, V <sub>R</sub> = 20 V		-	437	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	5.9	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	25	-	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

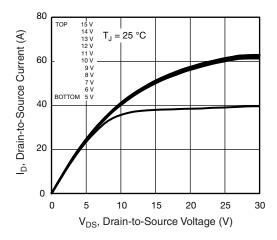


Fig. 1 - Typical Output Characteristics

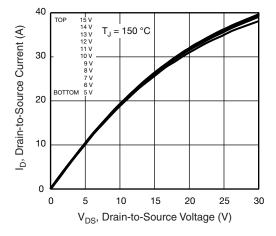


Fig. 2 - Typical Output Characteristics

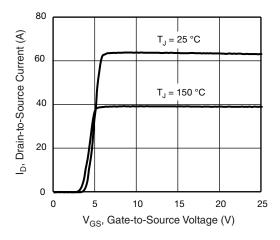


Fig. 3 - Typical Transfer Characteristics

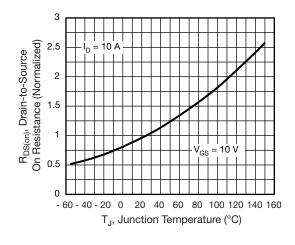


Fig. 4 - Normalized On-Resistance vs. Temperature

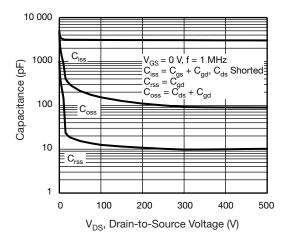


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

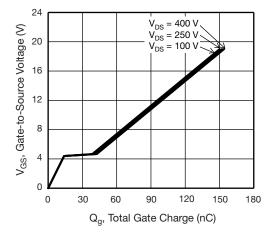


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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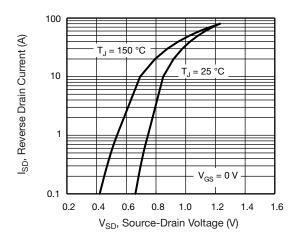


Fig. 7 - Typical Source-Drain Diode Forward Voltage

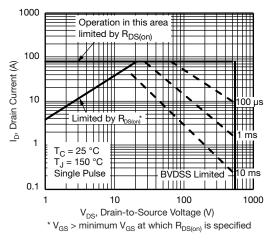


Fig. 8 - Maximum Safe Operating Area

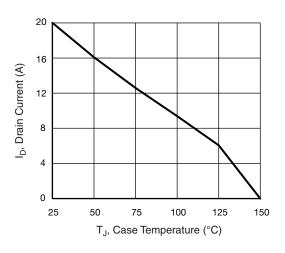


Fig. 9 - Maximum Drain Current vs. Case Temperature

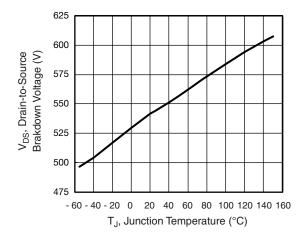


Fig. 10 - Temperature vs. Drain-to-Source Voltage

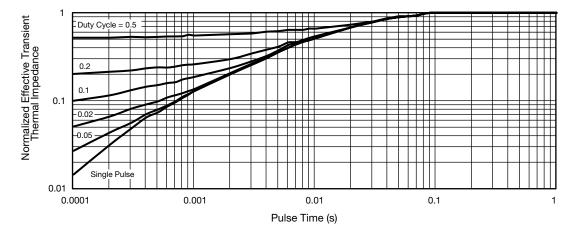


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



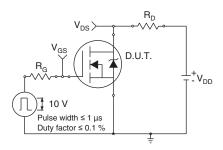


Fig. 12 - Switching Time Test Circuit

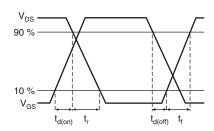


Fig. 13 - Switching Time Waveforms

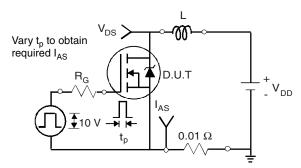


Fig. 14 - Unclamped Inductive Test Circuit

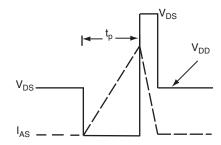


Fig. 15 - Unclamped Inductive Waveforms

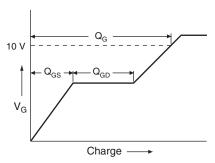


Fig. 16 - Basic Gate Charge Waveform

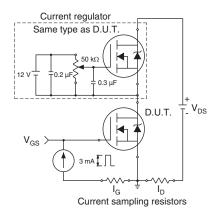
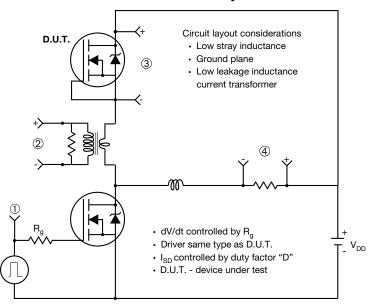


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



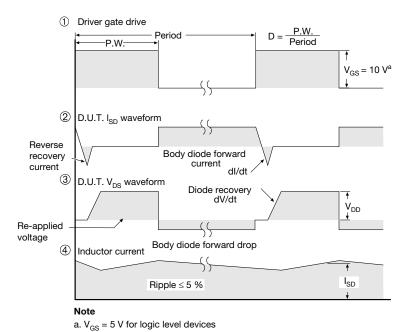
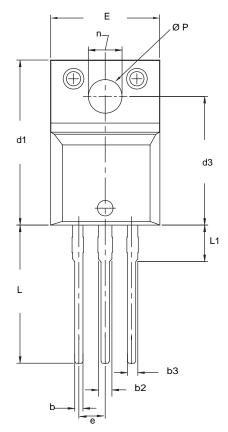
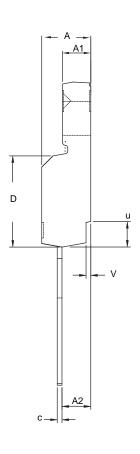


Fig. 18 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**





MIN.				
IVIIIN.	MAX.	MIN.	MAX.	
4.570	4.830	0.180	0.190	
2.570	2.830	0.101	0.111	
2.510	2.850	0.099	0.112	
0.622	0.890	0.024	0.035	
1.229	1.400	0.048	0.055	
1.229	1.400	0.048	0.055	
0.440	0.629	0.017	0.025	
8.650	9.800	0.341	0.386	
15.88	16.120	0.622	0.635	
12.300	12.920	0.484	0.509	
10.360	10.630	0.408	0.419	
2.54 BSC		0.100 BSC		
13.200	13.730	0.520	0.541	
3.100	3.500	0.122	0.138	
6.050	6.150	0.238	0.242	
3.050	3.450	0.120	0.136	
2.400	2.500	0.094	0.098	
0.400	0.500	0.016	0.020	
	2.570 2.510 0.622 1.229 1.229 0.440 8.650 15.88 12.300 10.360 2.54 13.200 3.100 6.050 3.050 2.400	2.570         2.830           2.510         2.850           0.622         0.890           1.229         1.400           1.229         1.400           0.440         0.629           8.650         9.800           15.88         16.120           12.300         12.920           10.360         10.630           2.54 BSC           13.200         13.730           3.100         3.500           6.050         6.150           3.050         3.450           2.400         2.500           0.400         0.500	2.570         2.830         0.101           2.510         2.850         0.099           0.622         0.890         0.024           1.229         1.400         0.048           1.229         1.400         0.048           0.440         0.629         0.017           8.650         9.800         0.341           15.88         16.120         0.622           12.300         12.920         0.484           10.360         10.630         0.408           2.54 BSC         0.100           13.200         13.730         0.520           3.100         3.500         0.122           6.050         6.150         0.238           3.050         3.450         0.120           2.400         2.500         0.094           0.400         0.500         0.016	

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.
   No chipping or package damage.

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